COSEL

SFCS1524/SFCS1548 EMI/EMS Test Result

参考資料

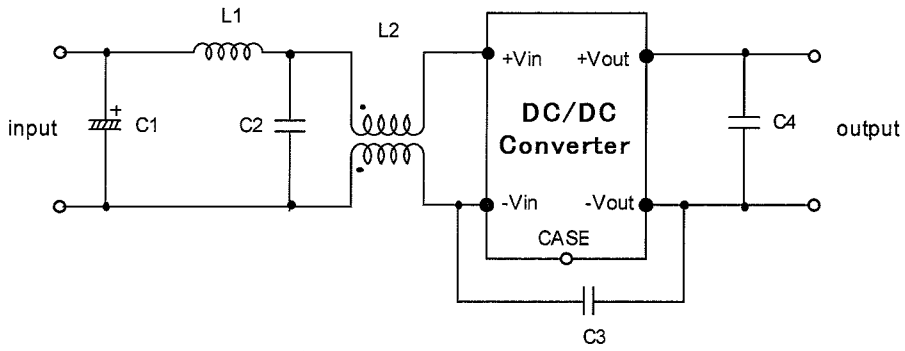
June 1, 2010
AS DESIGN DEPT

No.	Test item	Test conditions	Conditions of Acceptability	Result
1	Line conduction 雑音端子電圧	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. 25±10℃ 周囲温度 25±10℃ (4) Testing circuitry Fig.1, Fig.2 測定回路 図1, 図2	(1)Meets the undermentioned standard. VCCI classA CISPR11 classA , EN55011-A 下記規格に準拠していること VCCI classA CISPR11 classA , EN55011-A	OK
2	Radiated emission 放射電界強度	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. 25±10℃ 周囲温度 25±10℃ (4) Testing circuitry Fig.1, Fig.2 測定回路 図1, 図2	(1)Meets the undermentioned standard. VCCI classA CISPR11 classA , EN55011-A 下記規格に準拠していること VCCI classA CISPR11 classA , EN55011-A	OK
3	Static electricity immunity test (IEC61000-4-2) 静電気放電イミュニティ試験	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. 25±10℃ 周囲温度 25±10℃ (4) Contact discharge voltage 8kV Input,Output and case 8kV (Level 4) 印加電圧 入力・出力・ケース 8kV (Level 4) (5) Testing circuitry Fig.3 測定回路 図3	(1)The power supply is not stop. 停止しないこと (2)Circuit does not malfunction. 誤動作のないこと (3)No abnormality of the insulation destruction etc. 絶縁破壊など故障がないこと (4)Parts are no damaged. 部品の故障がないこと	OK
4	Radiated, radio-frequency, electromagnetic field immunity test (IEC61000-4-3) 放射性無線周波電磁界イミュニティ試験	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. 25±10℃ 周囲温度 25±10℃ (4)Testing field strength 10V/m (Level 3) 電界強度 10V/m (Level 3) (5) Testing circuitry Fig.3 測定回路 図3	(1)No protection circuit failure. 保護回路の故障がないこと (2)No output voltage drop with control circuit failure. 出力電圧の低下がないこと (3)No any other function failure 故障がないこと	OK
5	Electrical fast transient/ burst immunity test (IEC61000-4-4) 電気的ファーストトランジェントバーストイミュニティ試験	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. 25±10℃ 周囲温度 25±10℃ (4) Test peak voltage 4kV (Level 4) 印加電圧 4kV (Level 4) (5) Testing circuitry Fig.3 測定回路 図3	(1)No protection circuit failure. 保護回路の故障がないこと (2)No output voltage drop with control circuit failure. 出力電圧の低下がないこと (3)No any other function failure 故障がないこと	OK
6	Surge immunity test (IEC61000-4-5) サージイミュニティ試験	(1) Rated input 定格入力 (2) Rated load 定格負荷 (3) Ambient temp. 25±10℃ 周囲温度 25±10℃ (4) Test voltage Line to line ±2kV (Level 3) (5) Testing circuitry Fig.4 測定回路 図4	(1)The power supply is not stop. 停止しないこと (2)Circuit does not malfunction. 誤動作のないこと (3)No abnormality of the insulation destruction etc. 絶縁破壊など故障がないこと (4)Parts are no damaged. 部品の故障がないこと	OK

Approved : Toshiyuki Tsuri
Toshiyuki Tsuri

Prepared : K. Shibutani
Kenichi Shibutani

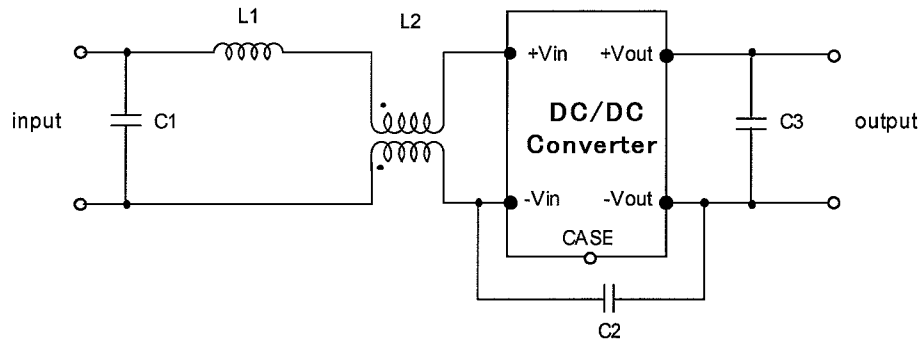
○EMI/EMS testing circuitry



C1 : 47μF 50V Electric capacitor
C2 : 1μF 100V Ceramic capacitor
C3 : 3R3/05 1000pF 630V Ceramic capacitor
: 12/15 2200pF 630V Ceramic capacitor
C4 : 3R3/05 22μF 16V Ceramic capacitor
: 12/15 0.1μF 50V Ceramic capacitor

L1 : 1μH 2.4A Inductor
(C4-K1.8R 1R0 MITSUMI) or equivalent.
L2 : ZJYS51R5-2P TDK or equivalent.

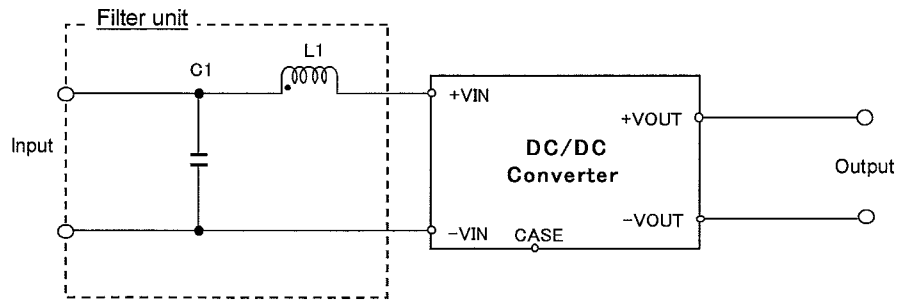
Fig.1 Testing circuitry (SFCS1524)



C1 : 1μF 100V Electric capacitor
C2 : 3R3/05 1000pF 630V Ceramic capacitor
: 12/15 2200pF 630V Ceramic capacitor
C3 : 3R3/05 22μF 16V Ceramic capacitor
: 12/15 0.1μF 50V Ceramic capacitor

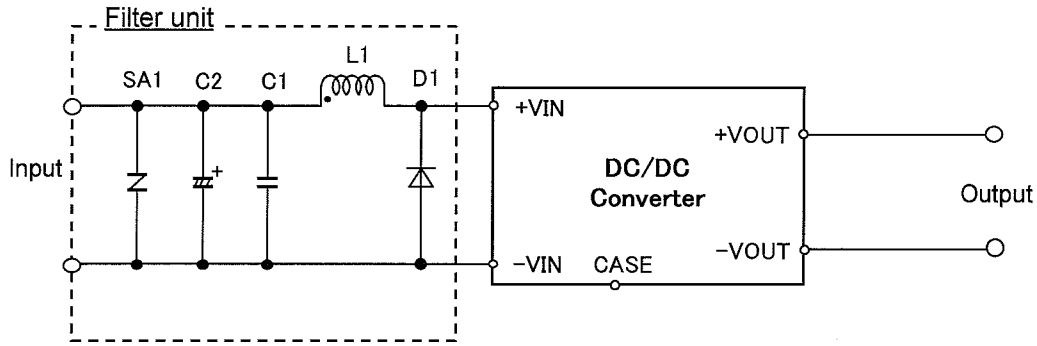
L1 : 1μH 2.4A Inductor
(C4-K1.8R 1R0 MITSUMI) or equivalent.
L2 : ZJYS51R5-2P TDK or equivalent.

Fig.2 Testing circuitry (SFCS1548)



C1 : 1μF 100V Ceramic capacitor
L1 : 1μH 2.4A Inductor(C4-K1.8R 1R0 MITSUMI) or equivalent.

Fig.3 Testing circuitry



C1 : 1μF 100V Ceramic capacitor
C2 : SFCS1524 270μF 50V Electric capacitor
: SFCS1548 330μF 100V Electric capacitor
L1 : 1μH 2.4A Inductor (C4-K1.8R 1R0 MITSUMI) or equivalent.
SA1 : SFCS1524 ERZV10D470 (PANASONIC CO.,LTD.)
: SFCS1548 ERZV10D101 (PANASONIC CO.,LTD.)
D1 : 200V, 3A (ERD32-02 Fuji Electric Device Technology) or equivalent.

Fig.4 Testing circuitry